

APPRAISER : DNN fault resilience analysis employing approximation errors

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DeepAxe : a framework for exploration of approximation and reliability trade-offs in DNN accelerators

Taheri, Mahdi; Riazati, Mohamad; Ahmadilivani, Mohammad Hasan; Jenihhin, Maksim; Daneshtalab, Masoud; Raik, Jaan; Sjödin, Mikael; Lisper, Björn arXiv.org 2023 / 8 p. : ill <https://doi.org/10.48550/arXiv.2303.0822>

A fault-resistant architecture for AES S-box architecture

Taheri, Mahdi; Sheikhpour, Saeideh; Ansari, Mohammad Saeed; Mahani, Ali Journal of Applied Research in Electrical Engineering 2021 / p. 86-92 <https://doi.org/10.22055/jaree.2021.36230.1020>

A high-performance MEMRISTOR-based Smith-Waterman DNA sequence alignment using FPN structure

Taheri, Mahdi; Zandevakili, Hamed; Mahani, Ali Journal of Applied Research in Electrical Engineering 2021 / p. 59-68
<https://doi.org/10.22055/jaree.2021.36117.1016>

A novel fault-tolerant logic style with self-checking capability

Taheri, Mahdi; Sheikhpour, Saeideh; Mahani, Ali; Jenihhin, Maksim Proceedings - 2022 IEEE 28th International Symposium on On-Line Testing and Robust System Design, IOLTS 2022 2022 / art. 183305 : ill <https://doi.org/10.1109/IOLTS56730.2022.9897818>